Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/655,211	WU, HAN WEN
Examiner	Art Unit

2875

James W. Cranson

	SEAR	CHED	
Class	Subclass	Date	Examiner
362	96	6/20/2006	JWC
362	101	6/20/2006	JWC
362	351	6/20/2006	JWC

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
	-		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
text 362/\$.ccls.	6/20/2006	JWC	